

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/643,078	NAKAZAWA ET AL.
Examiner	Art Unit	
David Q. Nguyen	2617	

ISSUE CLASSIFICATION

ORIGINAL			CROSS REFERENCE(S)								
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
455	63.1	455	67.13								
INTERNATIONAL CLASSIFICATION			370	278							
H	0	4	B	1/10/							
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<i>[Handwritten signatures and initials over rows 4-8]</i>											
<i>[Signature]</i> (Assistant Examiner) <i>10/30/06</i> (Date)				<i>[Signature]</i> JOSEPH FEIL SUPERVISORY PATENT EXAMINER (Primary Examiner) <i>10/30/06</i> (Date)				Total Claims Allowed: 5			
<i>[Signature]</i> (Legal Instruments Examiner) <i>10/30/06</i> (Date)								O.G. Print Claim(s)	O.G. Print Fig.		
								1	1		

Total Claims Allowed: 5

JOSEPH FETTER

10/3/2005

(Primary Examiner)

O.G.
Print Claim(s)

O.G.
Print Fig.

1

1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.I.4.7	
Final	Original	Final	Original	Final	Original	Final	Original
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5	5	35		65	95	125	155
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7	37			67	97	127	157
8	38			68	98	128	158
9	39			69	99	129	159
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